



## Description

### JMP N-channel Enhancement Mode Power MOSFET

#### Features

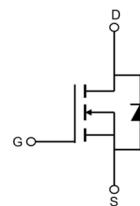
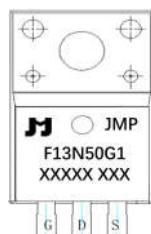
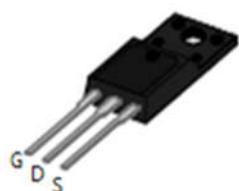
- 500V,13A
- $R_{DS(ON)} < 0.55\Omega$  @  $V_{GS} = 10V$
- Fast Switching
- Improved dv/dt Capability

#### Application

- Load Switch
- PWM Application
- Power management



100% UIS TESTED!  
100%  $\Delta V_{ds}$  TESTED!



TO-220FP top view

Marking and pin Assignment

Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	TUBE (PCS)	Inner Box (PCS)	Per Carton (PCS)
JMPF13N50G1	JMPF13N50G1	TUBE	TO-220FP	50	1,000	5,000

## Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		500	V
$V_{GSS}$	Gate-Source Voltage		$\pm 30$	V
$I_D$	Continuous Drain Current	$T_C = 25^\circ C$	13	A
		$T_C = 100^\circ C$	8.5	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		52	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>		259	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ C$	65	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.92	$^\circ C / W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient		62.5	$^\circ C / W$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150	$^\circ C$

**Electrical Characteristics** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

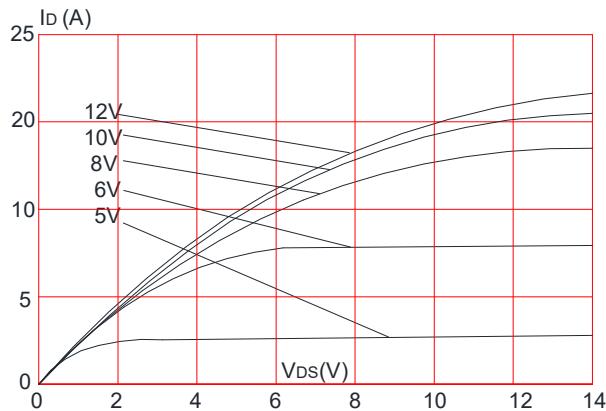
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	500	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{V}$ , $V_{GS} = 0\text{V}$ , $T_J = 25^\circ\text{C}$	-	-	1	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS} = 0\text{V}$ , $V_{GS} = \pm 30\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D=250\mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static Drain-Source on-Resistance note3	$V_{GS} = 10\text{V}$ , $I_D = 6.5\text{A}$	-	0.47	0.55	$\Omega$
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 1.0\text{MHz}$	-	1650	-	pF
$C_{oss}$	Output Capacitance		-	160	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	15	-	pF
$Q_g$	Total Gate Charge	$V_{DD} = 400\text{V}$ , $I_D = 13\text{A}$ , $V_{GS} = 10\text{V}$	-	35	-	nC
$Q_{gs}$	Gate-Source Charge		-	7	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	18	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 250\text{V}$ , $I_D = 13\text{A}$ , $R_G = 25\Omega$	-	23	-	ns
$t_r$	Turn-on Rise Time		-	15	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	90	-	ns
$t_f$	Turn-off Fall Time		-	30	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	13	-	A
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	52	-	A
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}$ , $I_{SD} = 13\text{A}$	-	-	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}$ , $I_S = 13\text{A}$ , $dI/dt = 100\text{A}/\mu\text{s}$	-	320	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	4.2	-	$\mu\text{C}$

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

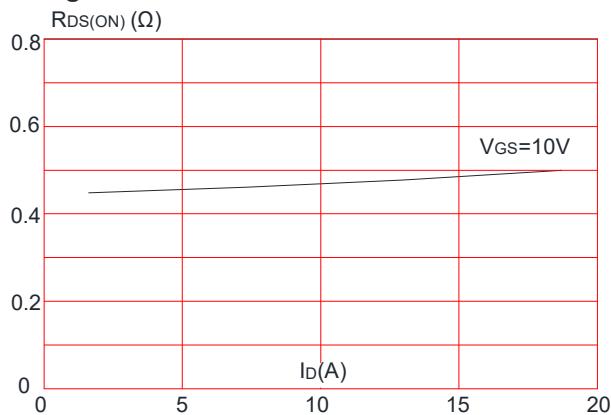
2. EAS condition:  $T_J = 25^\circ\text{C}$ ,  $V_{DD} = 50\text{V}$ ,  $V_G = 10\text{V}$ ,  $L = 10\text{mH}$ ,  $I_{AS} = 7.2\text{A}$ 3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 1\%$

## Typical Performance Characteristics

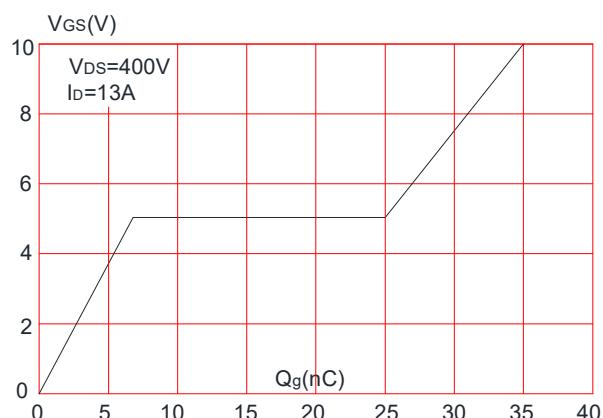
**Figure 1:** Output Characteristics



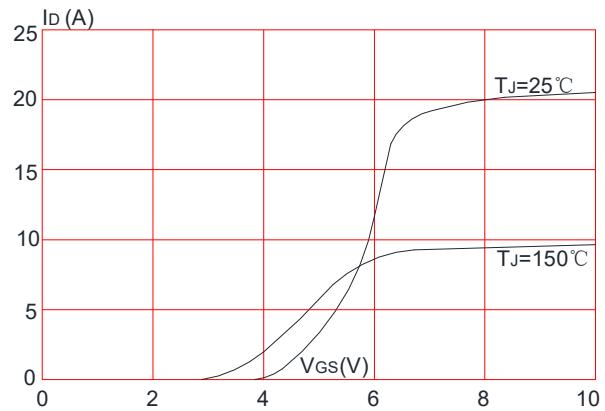
**Figure 3:** On-resistance vs. Drain Current



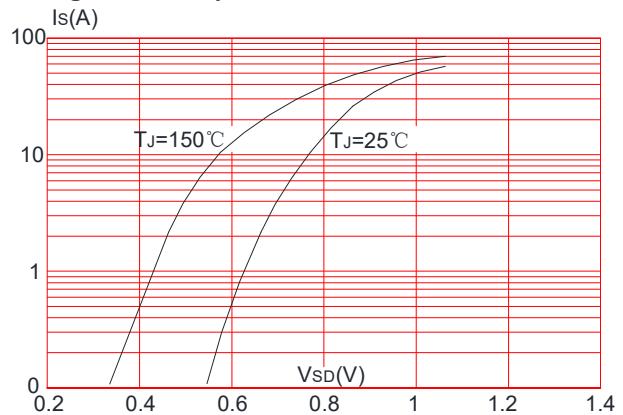
**Figure 5: Gate Charge Characteristics**



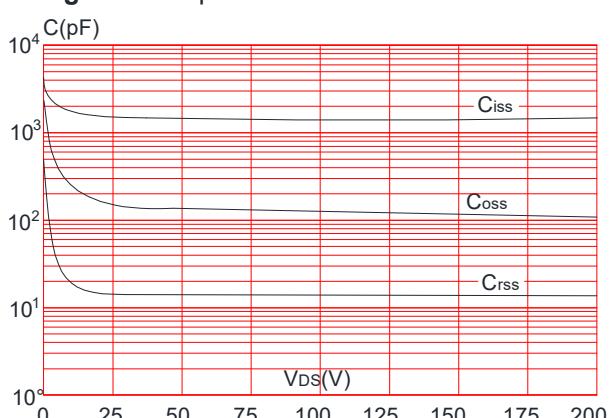
**Figure 2:** Typical Transfer Characteristics



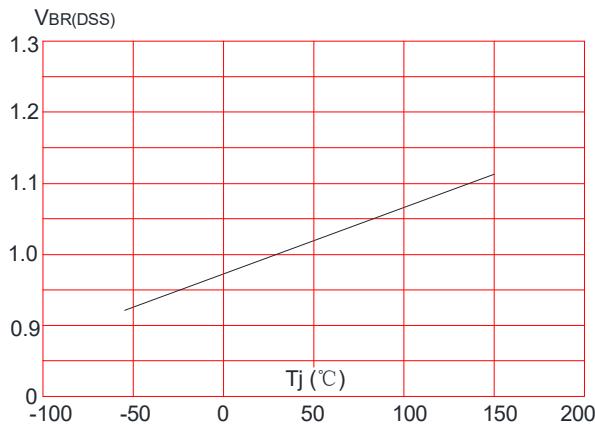
**Figure 4:** Body Diode Characteristics



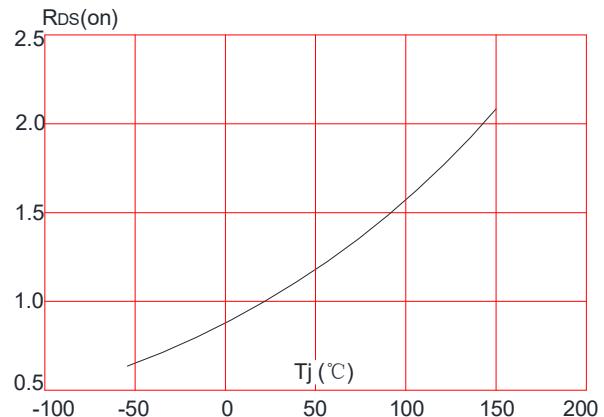
**Figure 6:** Capacitance Characteristics



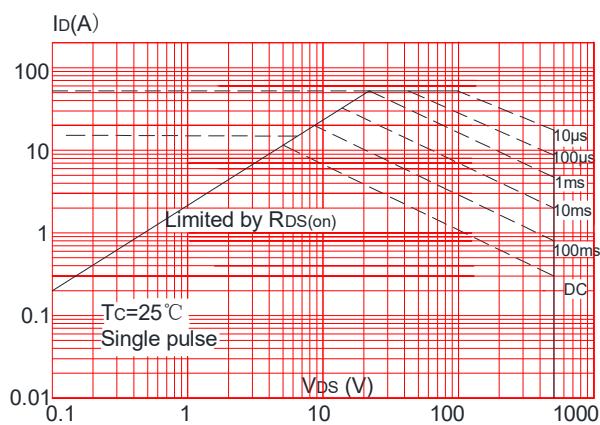
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



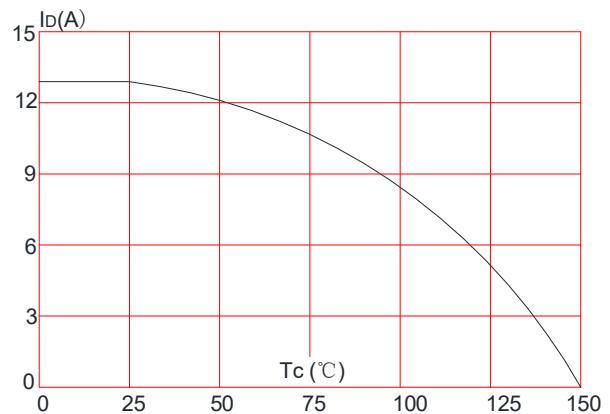
**Figure 8:** Normalized on Resistance vs. Junction Temperature



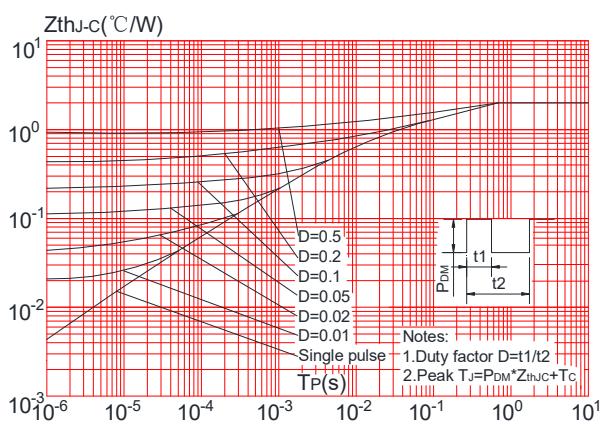
**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



## Test Circuit

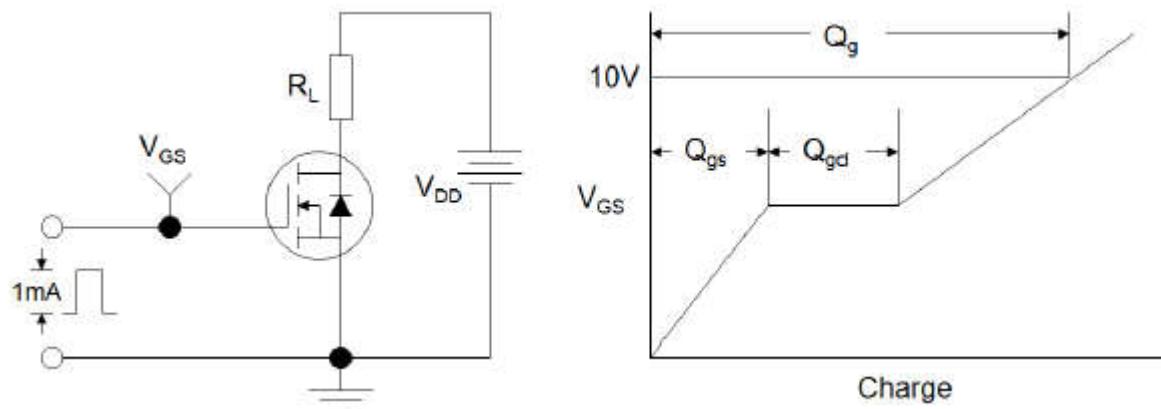


Figure1:Gate Charge Test Circuit & Waveform

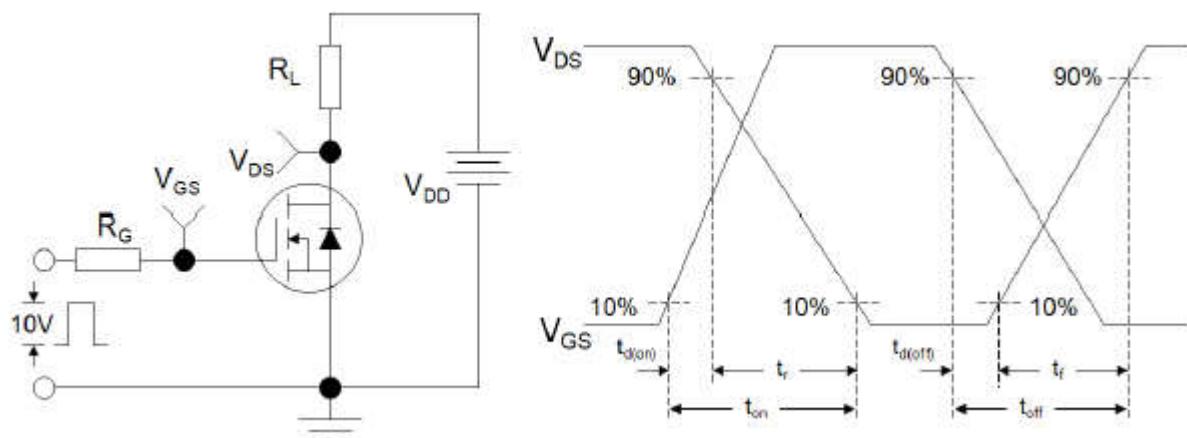


Figure 2: Resistive Switching Test Circuit & Waveforms

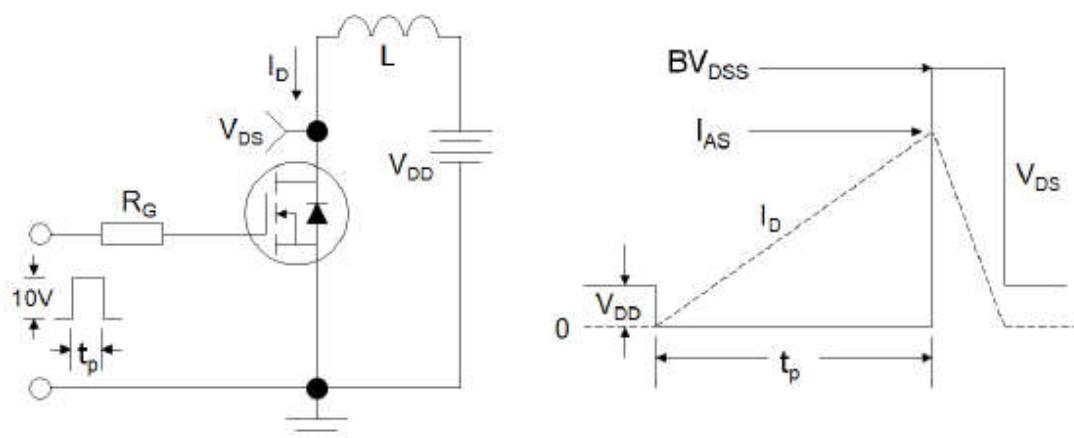
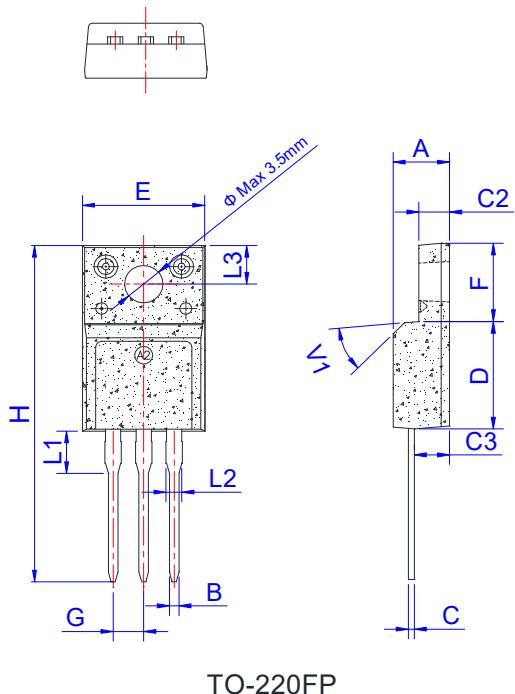


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

## Package Mechanical Data



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	4.50		4.90	0.177		0.193
B	0.74	0.80	0.83	0.029	0.031	0.033
C	0.47		0.65	0.019		0.026
C2	2.45		2.75	0.096		0.108
C3	2.60		3.00	0.102		0.118
D	8.80		9.30	0.346		0.366
E	9.80		10.4	0.386		0.410
F	6.40		6.80	0.252		0.268
G		2.54			0.1	
H	28.0		29.8	1.102		1.173
L1		3.63			0.143	
L2	1.14		1.70	0.045		0.067
L3		3.30			0.130	
V1		45°			45°	

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